

Search Notes

Application/Control No.

10/529,854

Examiner

BIN SHEN

Applicant(s)/Patent under
Reexamination

TANAKA, KOJIRO

Art Unit

1657

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated search.	4/2/2008	BS